Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/691,212	DORNBUSCH ET AL.	
Examiner	Art Unit	
Chris C. Chu	2815	

		 		
SEARCHED				
Class	·Subclass	Date	Examiner	
257	E23.052, E23.079, 786 & 778	1/29/2007	C.C.	
310	313	1/29/2007	C.C.	
333	193 & 194	1/29/2007	C.C.	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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(INCLUDING SEARCH	STRATEGY	
·	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	1/29/2007	C.C.